Electronic Forensic Techniques for Manufacturer Attribution

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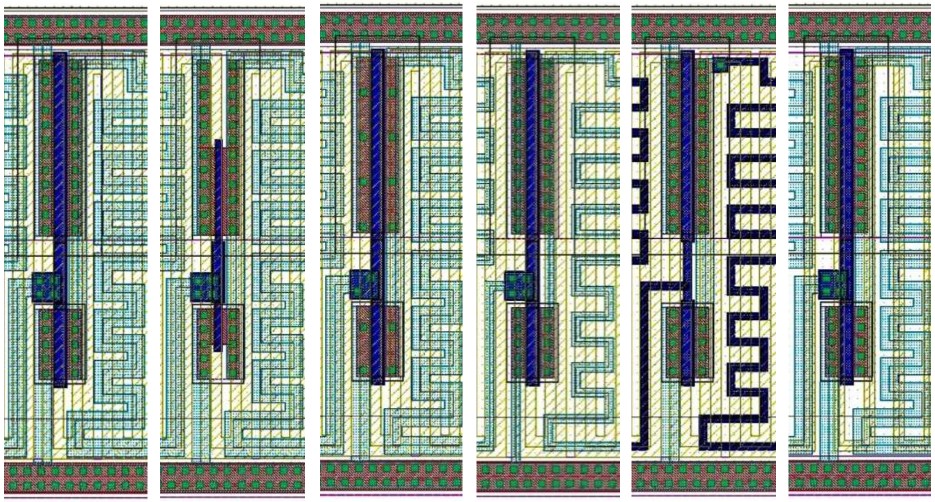
- Novel techniques presented
  - to measure multiple distinct manufacturing process variations
  - using self-contained, on-chip hardware (e.g., ring oscillators)



- Analysis of 159 silicon ICs
  - built as a proof of concept
  - 80 copies built at one fab
  - 80 more copies were built in two lots at a second fab
- Classification predictions
  - two fabs with up to 98.7% accuracy
  - two lots from the second fab with up to 98.8% accuracy

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